

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Takashi Nakano et al.

Examiner: unassigned

Serial No.: 10/518,157

Art Unit: 2812

Filed: December 10, 2004

Docket: 18497

For: SEMICONDUCTOR DEVICE, SEMICONDUCTOR
CIRCUIT AND METHOD OF FABRICATING
SEMICONDUCTOR DEVICE **Dated:** March 31, 2005

Confirmation No.: 3521

Mailstop Amendment
Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

In accordance with 37 C.F.R. §§1.97 and 1.98, it is requested that the following references, which are also listed on the attached Form PTO-1449, be made of record in the above-identified case.

1. Japanese Laid Open Patent Application 09-208627 dated August 12, 1997;
2. Japanese Laid Open Patent Application 2002-009244 dated January 11, 2002;
3. Japanese Laid Open Patent Application 05-160334 dated June 25, 1993;

CERTIFICATE OF MAILING UNDER 37 C.F.R. § 1.8(a)

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, P. O. Box 1450, Alexandria, VA 22313-1450 on March 31, 2005.

Dated: March 31, 2005



Paul J. Esatto, Jr.

4. Japanese Laid Open Patent Application 2001-203455 dated July 27, 2001;
5. Japanese Laid Open Patent Application 08-316404 dated November 29, 1996;
6. Japanese Laid Open Utility Model Application 53-164659 dated December 23, 1978; and
7. Japanese Laid Open Patent Application 2002-026272 dated January 25, 2002.

The references were cited in a first Office Actions dated September 2, 2003 and a second Office Action dated March 16, 2004 received from the Japanese Patent Office.

Applicants are submitting copies of the above-cited references, together with an English translation of the Examiner's comments regarding the references from the Official Action. The relevance of the references is described in the Official Action. Please note that the references listed in the Japanese Office Actions and not provided herewith were previously submitted in an Information Disclosure Statement dated December 10, 2004.


In compliance with the requirements of 37 C.F.R. §1.98(a)(3), as a concise statement of relevance, as it is presently understood by the individual designated in 37 C.F.R. §1.56(c) most knowledgeable about the content of the information, the undersigned attorney of record submits a translation of portions of an official action dated September 2, 2003 and March 16, 2004 by a foreign examiner in which the references were cited. The relevance to the pending U.S. patent application is that the references were cited in a foreign patent application on the same subject matter. However, no independent analysis of the references, the accuracy of the statement of the foreign examiner or the claims of the foreign application under the laws of that country or the United States relative to the subject matter claimed in the present application has

been made; the present understanding of the contents thereof by the undersigned being based on the translation of the foreign examiner's comments submitted herewith.

Also enclosed herewith is a Translation of the International Preliminary Examination Report. The Japanese International Preliminary Examination Report was filed on December 10, 2004.

Inasmuch as this Information Disclosure Statement is being submitted in accordance with the schedule set out in 37 C.F.R. § 1.97(b), no statement or fee is required.

Respectfully submitted,



Paul J. Esatto, Jr.
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PJE:ae

Form **PTO-1449** U.S. DEPARTMENT OF COMMERCE
(REV. 7-80) PATENT AND TRADEMARK OFFICE**INFORMATION DISCLOSURE CITATION***(Use several sheets if necessary)***Atty. Docket No. (Optional)**

18497

Application Number

10/518,157

Applicant(s)

Takashi Nakano et al.

Filing Date

December 10, 2004

Group Art Unit

2812

U.S. PATENT DOCUMENTS

EXAMINER INITIAL*	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (if appropriate)

FOREIGN PATENT DOCUMENTS

REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
	9-208627	8/12/97	Japan				
	2002-009244	1/11/02	Japan				
	5-160334	6/25/93	Japan				
	2001-203455	7/27/01	Japan				
	8-316404	11/29/96	Japan				
	53-164659	12/23/78	Japan				
	2002-26272	1/25/02	Japan				

OTHER DOCUMENTS *(Including Author, Title, Date, Pertinent Pages, Etc.)*

EXAMINER**DATE CONSIDERED**

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.